

Search Notes

Application/Control No.

09/712,855

Examiner

Christopher A. Revak

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2131

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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| 714 | 5,6,16,17 | 2/16/2005 | CR |
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| 380 | 44,277 | 2/16/2005 | CR |
| 713/168,176,181- 185,200 | | 2/16/2005 | cr |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PG PUB, USOCR | 9/9/2005 | CR |
| DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE | 9/9/2005 | CR |
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Search Notes (continued)

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INTERFERENCE SEARCHED

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| 707 | 1,9 | 2/16/2005 | CR |
| 707 | 200-204 | 2/16/2005 | CR |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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